



Slovenski inštitut za  
kakovost in meroslovje  
Slovenian Institute of  
Quality and Metrology

# Poročilo o preskusu / Test Report

Št. / No.:

T211-0477/12

Datum / Date:

2012-10-08

<b>Proizvod / Product</b> Power supply Model: GT-81082-WVVV-X.X-W2Z series GT-81090-WVVV-X.X-W2Z series Enclosure: WR95A1000USB-F(R)	<b>Listov / Pages</b> 2
<b>Naročnik / Applicant</b> GlobTek, Inc 186 Veterans Dr, Northvale, NJ 07647 / USA	<b>Vrsta preskusa / Test procedure</b> IP20
<b>Proizvajalec / Manufacturer</b> GlobTek, Inc 186 Veterans Dr, Northvale, NJ 07647 / USA	<b>Št. Merjencev / No. of Items tested</b> 1
<b>Blagovna znamka / Trade Mark</b> GlobTek	<b>Mapa predmeta št. / Subject File No.</b> C20121557
<b>Standardi – predpisi / Standards - regulations</b> IEC 60529:2001	<b>Kraj preskusa / Place of test</b> SIQ - Slovenian Institute of Quality and Metrology, Tržaška 2, 1000 Ljubljana, Slovenia
	<b>Opomba / Remark</b> /

## Zaključek / Conclusion

**Tested product complies with the requirements of stated standards for protection degree IP 20.**

*The test results relate only to the items tested.*

Date of receipt of test items: 2012-07-16

Date of performance of tests: 2012-07-16 to 2012-09-19

Testni laboratorij je akreditiran pri Slovenski akreditaciji, reg.št.: LP-009 /  
Testing Laboratory is accredited by Slovenian Accreditation, Reg. No. LP-009

Odgovoren za preskušanje / Responsible for the test

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## 1 TEST EQUIPMENT

- Jointed test finger ID6 as specified by the standard,
- Rigid test wire diameter of 12.5 mm as specified by the standard (2014-07-27)

Note: The date of the recommended recalibration is given for each measuring instrument (in brackets).

## 2 EQUIPMENT UNDER TEST (EUT)

Power supply, model GT-81082-WWVV-X.X-W2Z series and GT-81090-WWVV-X.X-W2Z series, enclosure WR95A1000USB-F(R) was subjected to testing for IP20 degree of protection (Figures 1 and 2).



Figure 1



Figure 2

### IP20 numeric description:

The first characteristic numeral X: indicates the degree of protection against access to hazardous parts and against solid foreign objects. Test equipment for degree 2 is test finger of 12 mm diameter and 80 mm long and rigid test wire of 12.5 mm diameter. The protection is satisfactory if the probe does not fully penetrate and adequate clearance is kept.

## 3 TEST CONDITIONS

### 3.1 Test for protection against access to hazardous parts and against solid foreign objects-IP2X (IEC 60529, tables 2 and 7, sub-cl. 13.2)

Procedure:

- Environmental temperature 23<sup>0</sup>C,
- The jointed test finger is pushed against any openings of the enclosure with the force of 10 N,
- Rigid test wire diameter of 12.5 mm (as specified by the standard) is pushed against any openings of the enclosure with the force of 30 N,
- Non-operating condition.

**Conclusion:** The jointed test finger and the rigid test wire were not penetrated into the enclosure.

## 4 CONCLUSIONS

After the exposure was concluded, the visual examination of the sample was performed. Results were obtained as follows:

- The jointed test finger and the rigid test wire were not penetrated into the enclosure

**Result: Following the acceptance conditions, the equipment under test sustained the test conditions for IP20 degree of protection.**